SN74F169 SYNCHRONOUS 4-BIT UP/DOWN BINARY COUNTER

SDFS089 - MARCH 1987 - REVISED OCTOBER 1993

- Fully Synchronous Operation for Counting and Programming
- Internal Look-Ahead Circuitry for Fast Counting
- Carry Output for N-Bit Cascading
- Fully Independent Clock Circuit
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

(TOP VIEW) U/D V_{CC} CLK 15 RCO 2 14 🛮 Q_A Α 3 В 13 L Q_B 12 🛮 Q_C С 11 🛛 Q_D D ENP 10 | ENT **GND** 9 LOAD

D OR N PACKAGE

description

This synchronous, presettable, 4-bit up/down binary counter features an internal carry look-ahead circuitry for cascading in high-speed counting applications. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincident with each other when so instructed by the count-enable (ENP, ENT) inputs and internal gating. This mode of operation eliminates the output counting spikes that are normally associated with asynchronous (ripple-clock) counters. A buffered clock (CLK) input triggers the four flip-flops on the rising (positive-going) edge of the clock waveform.

This counter is fully programmable; that is, it may be preset to any number between 0 and its maximum count. The load-input circuitry allows loading with the carry-enable output of cascaded counters. As loading is synchronous, setting up a low level at the load (LOAD) input disables the counter and causes the outputs to agree with the data inputs after the next clock pulse.

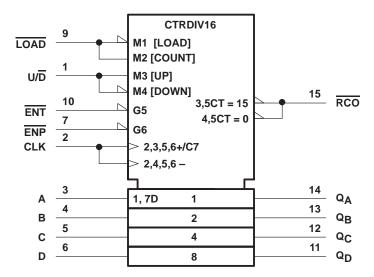
The carry look-ahead circuitry provides for cascading counters for n-bit synchronous application without additional gating. Instrumental in accomplishing this function are two count-enable (\overline{ENP} , \overline{ENT}) inputs and a ripple-carry (\overline{RCO}) output. Both \overline{ENP} and \overline{ENT} must be low to count. The direction of the count is determined by the level of the up/down (U/ \overline{D}) input. When U/ \overline{D} is high, the counter counts up; when low, it counts down. Input \overline{ENT} is fed forward to enable the \overline{RCO} . \overline{RCO} thus enabled will produce a low-level pulse while the count is zero (all inputs low) counting down or maximum (9 or 15) counting up. This low-level overflow ripple-carry pulse can be used to enable successive cascaded stages. Transitions at \overline{ENP} or \overline{ENT} are allowed regardless of the level of the clock input. All inputs are diode clamped to minimize transmission-line effects, thereby simplifying system design.

The SN74F169 features a fully independent clock circuit. Changes at control inputs ($\overline{\text{ENP}}$, $\overline{\text{ENT}}$, $\overline{\text{LOAD}}$ or $\overline{\text{U/D}}$) that will modify the operating mode have no effect on the contents of the counter until clocking occurs. The function of the counter (whether enabled, disabled, loading, or counting) will be dictated solely by the conditions meeting the setup and hold times.

The SN74F169 is characterized for operation from 0°C to 70°C.

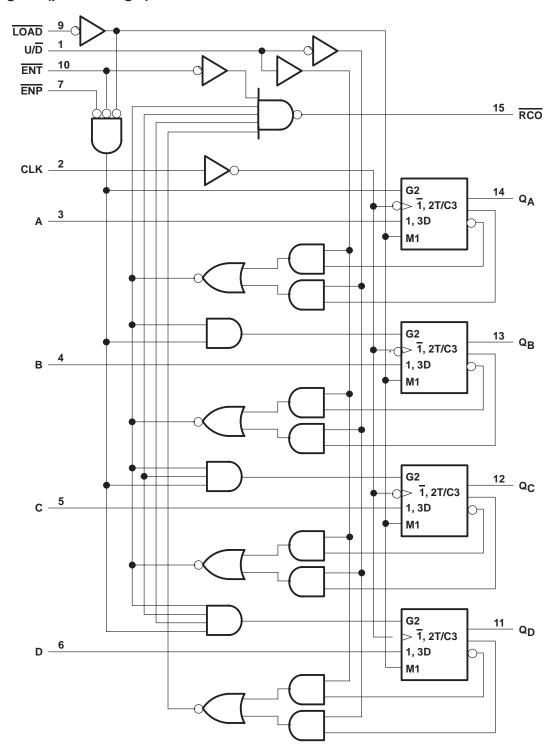


logic symbol†

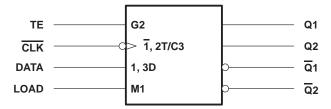


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

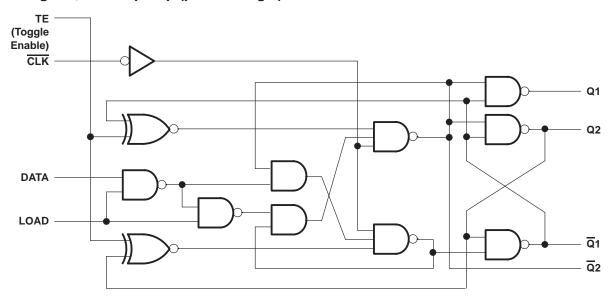
logic diagram (positive logic)



logic symbol, each flip-flop



logic diagram, each flip-flop (positive logic)



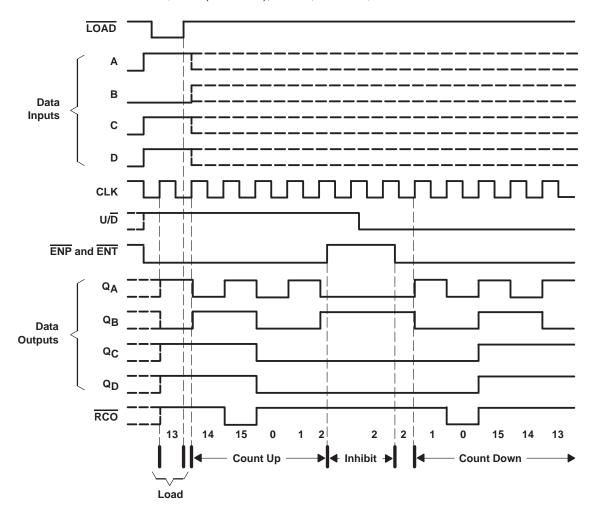
FUNCTION TABLE (each flip-flop)

COUNTER INPUTS		FLIP-FLOP INPUTS				OUTPUTS		
LOAD	CLK	LOAD	TE	CLK	DATA	Q	Q	
L	↑	Н	L	\downarrow	Н	Н	L	
L	\uparrow	Н	L	\downarrow	L	L	Н	
н	\uparrow	L	Н	\downarrow	Х	\overline{Q}_0	Q_0	
н	\uparrow	L	L	\downarrow	Χ	Q_0	\overline{Q}_0	

typical load, count, and inhibit sequences

Illustrated below is the following sequence:

- 1. Load (preset) to binary thirteen
- 2. Count up to fourteen, fifteen (maximum), zero, one, and two
- 3. Inhibit
- 4. Count down to one, zero (minimum), fifteen, fourteen, and thirteen



SDFS089 - MARCH 1987 - REVISED OCTOBER 1993

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
lik	Input clamp current			-18	mA
ЮН	High-level output current			– 1	mA
loL	Low-level output current			20	mA
T _A	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			TYP‡	MAX	UNIT	
VIK		$V_{CC} = 4.5 \text{ V},$	$I_{\parallel} = -18 \text{ mA}$			-1.2	V	
VOH		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		٧	
		V _{CC} = 4.75 V,	$I_{OH} = -1 \text{ mA}$	2.7				
VOL		V _{CC} = 4.5 V,	I _{OL} = 20 mA		0.3	0.5	V	
Ц		V _{CC} = 5.5 V,	V _I = 7 V			0.1	mA	
lіН		$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20	μΑ	
1	ENT	V 55V	V: 0.5.V			- 1.2	mA	
II∟	All others	V _{CC} = 5.5 V,	$V_{I} = 0.5 V$			- 0.6	IIIA	
IOS§		$V_{CC} = 5.5 \text{ V},$	V _O = 0	-60		-150	mA	
Icc		V _{CC} = 5.5 V,	See Note 2		38	52	mA	

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

NOTE 2: ICC is measured after applying a momentary 4.5 V, then ground, to the clock input with B and ENT inputs high and all other inputs low.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

SDFS089 - MARCH 1987 - REVISED OCTOBER 1993

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

				V _{CC} =	= 5 V, 25°C	MIN	MAX	UNIT	
				MIN	MAX				
fclock	Clock frequency			0	100	0	90	MHz	
t _W	Pulse duration	CLK high or low		5		5.5		ns	
		Data before CLK↑	High or low	4		4.5			
		LOAD before CLK↑	High or low	8		9			
t _{su}	Setup time	ENP and ENT before CLK↑	High or low	5		6		ns	
		II/□ h ofore CLIK↑	High	11		12.5			
		U/D before CLK↑	Low	7		8			
	Hold time	Data after CLK↑	High or low	3		3.5			
t _h		LOAD after CLK↑	High or low	0		0		ns	
		ENP and ENT after CLK↑	High or low	0		0		115	
		U/D after CLK↑	High or low	0		0			

switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_{L} = 50 pF, R_{L} = 500 Ω, T_{A} = 25°C			$V_{CC} = 4.5$ $C_L = 50 \text{ pF}$ $R_L = 500 \Omega$ $T_A = \text{MIN t}$	UNIT	
			MIN	TYP	MAX	MIN	MAX	
f _{max}			100	115		90		MHz
t _{PLH}	CLK	0	2.2	6.1	8.5	2.2	9.5	ns
^t PHL		Q	3.2	8.6	11.5	3.2	13	115
^t PLH	CLK	RCO	4.7	11.6	15.5	4.7	17	ns
t _{PHL}		RCO	3.2	8.1	11	3.2	12.5	115
^t PLH	ENT	RCO	1.7	4.1	6	1.7	7	ns
^t PHL			1.7	5.6	8	1.7	9	
^t PLH	U/D	RCO	2.7	8.1	11	2.7	12.5	ns
^t PHL		KCO	3.2	7.6	10.5	3.2	12	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



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